

# **Opti**MOS<sup>™</sup>3 Power-Transistor

### **Features**

- Very low gate charge for high frequency applications
- Optimized for dc-dc conversion
- N-channel, normal level
- Excellent gate charge x R DS(on) product (FOM)
- Very low on-resistance R DS(on)
- 150 °C operating temperature
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target application
- Halogen-free according to IEC61249-2-21

### **Product Summary**

$V_{\mathrm{DS}}$	100	٧
R <sub>DS(on),max</sub>	6	mΩ
I <sub>D</sub>	90	Α

PG-TDSON-8









Туре	Package	Marking	
BSC060N10NS3 G	PG-TDSON-8	060N10NS	

**Maximum ratings,** at  $T_i$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C	90	Α
		T <sub>C</sub> =100 °C	66	
		T <sub>A</sub> =25 °C, R <sub>thJA</sub> =50 K/W <sup>2)</sup>	14.9	
Pulsed drain current <sup>3)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	360	
Avalanche energy, single pulse	E <sub>AS</sub>	$I_{\rm D}$ =50 A, $R_{\rm GS}$ =25 $\Omega$	230	mJ
Gate source voltage	$V_{GS}$		±20	V
Power dissipation	P <sub>tot</sub>	T <sub>C</sub> =25 °C	125	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 150	°C
IEC climatic category; DIN IEC 68-1			55/150/56	



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R <sub>thJC</sub>		-	-	1	K/W
Thermal resistance,	R <sub>thJA</sub>	minimal footprint	-	-	62	
junction - ambient		6 cm <sup>2</sup> cooling area <sup>2)</sup>	-	-	50	

# **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

### Static characteristics

Drain-source breakdown voltage V		V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	100	-	-	V
Gate threshold voltage V <sub>GS(th)</sub>		V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =90 μA	2	2.7	3.5	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C	1	0.01	1	μΑ
		V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	-	10	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	1	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10 V, I <sub>D</sub> =50 A	-	5.3	6	mΩ
		V <sub>GS</sub> =6 V, I <sub>D</sub> =25 A	-	6.6	11.5	
Gate resistance	R <sub>G</sub>		-	1.6	-	Ω
Transconductance $g_{f}$		$ V_{\rm DS}  > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 50~{\rm A}$	43	85	-	s

<sup>1)</sup>J-STD20 and JESD22

 $<sup>^{2)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.

<sup>3)</sup> see figure 3



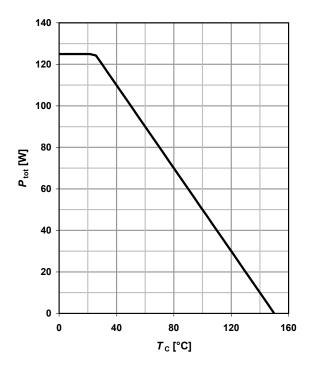
Parameter	Symbol	Symbol Conditions		Values		
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss		-	3700	4900	pF
Output capacitance	C oss	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, f=1 MHz	-	650	860	
Reverse transfer capacitance	C <sub>rss</sub>	]	1	25	-	
Turn-on delay time	t <sub>d(on)</sub>		-	20	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =50 V, V <sub>GS</sub> =10 V,	-	16	-	
Turn-off delay time	$t_{\text{d(off)}}$	$I_{\rm D}$ =25 A, $R_{\rm G}$ =1.6 Ω	-	45	-	
Fall time	t <sub>f</sub>	]	-	12	-	1
Gate Charge Characteristics <sup>4)</sup>		T		l		
Gate to source charge	Q <sub>gs</sub>		-	15	-	nC
Gate to drain charge	$Q_{\rm gd}$	1, 50,7, 05,4	-	9	-	
Switching charge	$Q_{sw}$	V <sub>DD</sub> =50 V, I <sub>D</sub> =25 A, V <sub>GS</sub> =0 to 10 V	ı	13	-	
Gate charge total	Q <sub>g</sub>		ı	51	68	
Gate plateau voltage	$V_{\rm plateau}$		-	4.2	-	٧
Output charge	Q oss	V <sub>DD</sub> =50 V, V <sub>GS</sub> =0 V	-	68	91	nC
Reverse Diode						
Diode continous forward current	Is	T -25 °C	-	-	90	Α
Diode pulse current	I <sub>S,pulse</sub>	- T <sub>C</sub> =25 °C	-	-	360	
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =50 A, T <sub>j</sub> =25 °C	-	1	1.2	V
Reverse recovery time	t rr	V <sub>R</sub> =50 V, I <sub>F</sub> =25 A,	-	61	-	ns
		d <i>i</i> <sub>F</sub> /d <i>t</i> =100 A/μs	-	109	-	nC

<sup>&</sup>lt;sup>4)</sup> See figure 16 for gate charge parameter definition



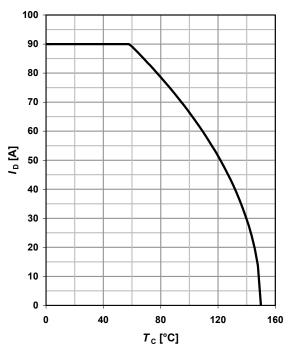
### 1 Power dissipation

$$P_{\text{tot}}$$
=f( $T_{\text{C}}$ )



### 2 Drain current

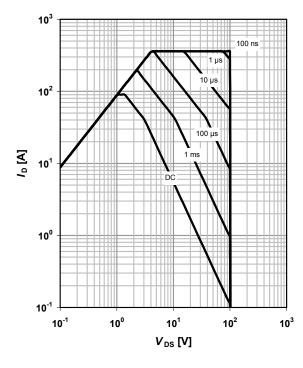
$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$



# 3 Safe operating area

$$I_D = f(V_{DS}); T_C = 25 °C; D = 0$$

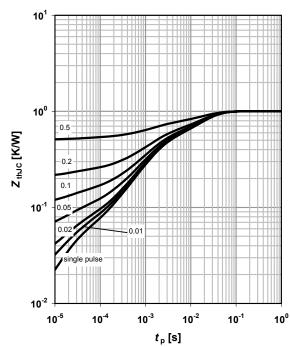
parameter:  $t_{\rm p}$ 



# 4 Max. transient thermal impedance

$$Z_{thJC}$$
=f( $t_p$ )

parameter:  $D = t_p/T$ 

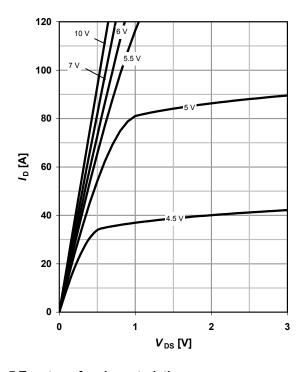




### 5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C$ 

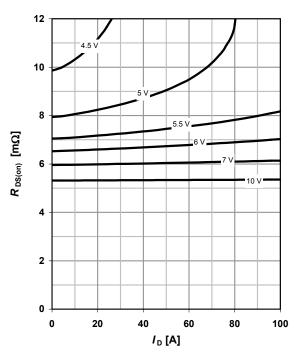
parameter:  $V_{\rm GS}$ 



# 6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =25 °C

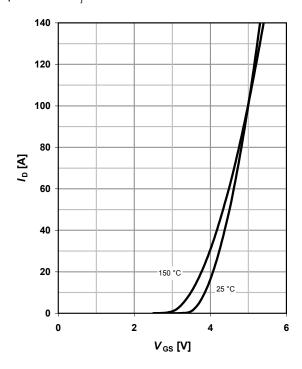
parameter:  $V_{\rm GS}$ 



# 7 Typ. transfer characteristics

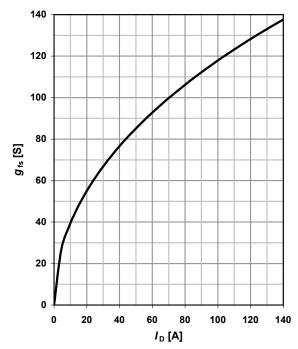
 $I_{D}$ =f( $V_{GS}$ );  $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$ 

parameter:  $T_{\rm j}$ 



# 8 Typ. forward transconductance

$$g_{fs}$$
=f( $I_D$ );  $T_j$ =25 °C





### 9 Drain-source on-state resistance

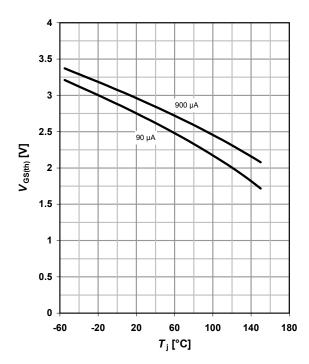
$$R_{DS(on)}$$
=f( $T_j$ );  $I_D$ =50 A;  $V_{GS}$ =10 V

# 12 10 8 8 98 % 4 2 0 -60 -20 20 60 100 140 180 $T_j$ [°C]

# 10 Typ. gate threshold voltage

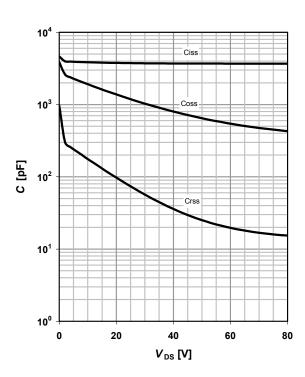
$$V_{GS(th)}$$
=f( $T_j$ );  $V_{GS}$ = $V_{DS}$ 

parameter:  $I_D$ 



# 11 Typ. capacitances

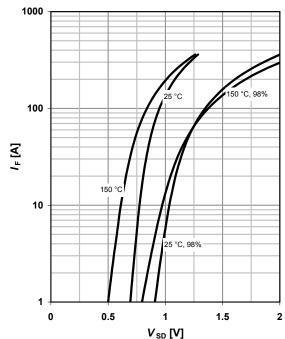
$$C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$$



### 12 Forward characteristics of reverse diode

$$I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$$

parameter:  $T_{\rm j}$ 





### 13 Avalanche characteristics

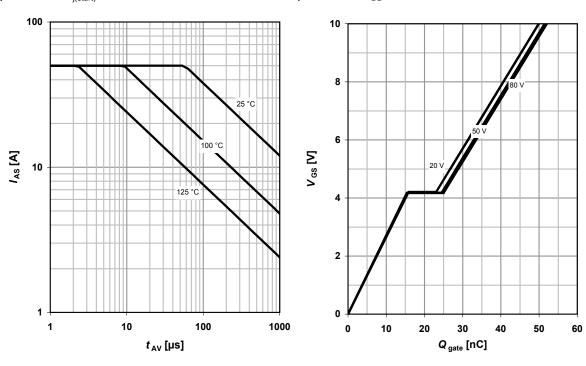
 $I_{\mathsf{AS}}$ =f( $t_{\mathsf{AV}}$ );  $R_{\mathsf{GS}}$ =25  $\Omega$ 

parameter:  $T_{j(start)}$ 

# 14 Typ. gate charge

 $V_{\rm GS}$ =f(Q  $_{\rm gate}$ );  $I_{\rm D}$ =25 A pulsed

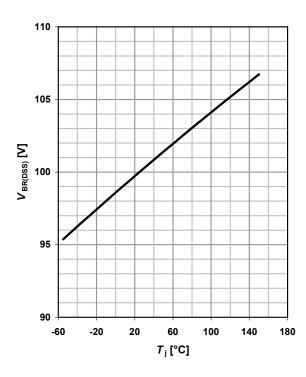
parameter:  $V_{\rm DD}$ 

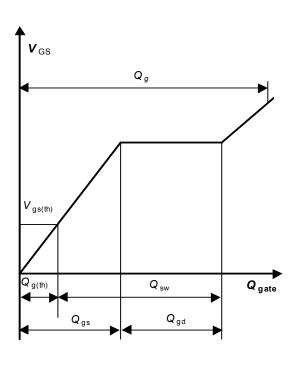


# 15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_i); I_D=1 \text{ mA}$ 

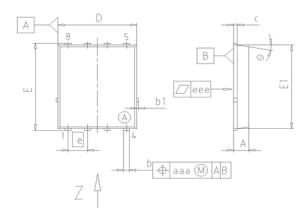
# 16 Gate charge waveforms

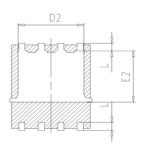


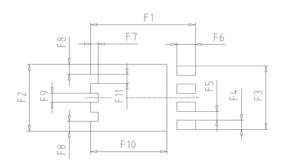


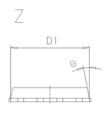


### Package Outline: PG-TDSON-8

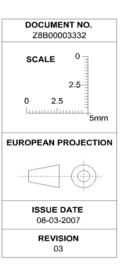




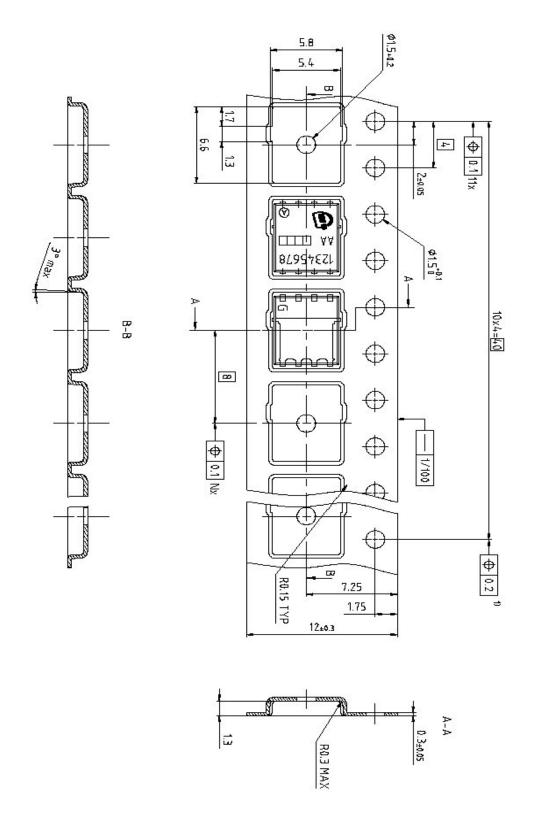




DIM	MILLIM	ETERS	INCH	IES		
DIM	MIN	MAX	MIN	MAX		
Α	0.90	1.10	0.035	0.043		
b	0.34	0.54	0.013	0.021		
b1	0.02	0.22	0.001	0.008		
С	0.15	0.35	0.006	0.014		
D=D1	4.95	5.35	0.195	0.211		
D2	4.20	4.40	0.165	0.173		
E	5.95	6.35	0.234	0.250		
E1	5.70	6.10	0.224	0.240		
E2	3.40	3.80	0.134	0.150		
е	1.2	27	0.050			
N	,	8		8		
L	0.45	0.65	0.018	0.026		
	8.5°	11.5°	8.5°	11.5°		
aaa	0.2	25	0.010			
eee	0.0	0.05		02		
F1	6.75	6.95	0.266	0.274		
F2	4.60	4.80	0.181	0.189		
F3	4.36	4.56	0.172	0.180		
F4	0.55	0.75	0.022	0.030		
F5	0.52	0.72	0.020	0.028		
F6	1.10	1.30	0.043	0.051		
F7	0.40	0.60	0.016	0.024		
F8	0.60	0.80	0.024	0.031		
F9	0.53	0.73	0.021	0.029		
F10	4.90	5.10	0.193	0.201		
F11	0.53	0.73	0.021	0.029		







Dimensions in mm



Published by Infineon Technologies AG 81726 Munich, Germany © 2009 Infineon Technologies AG All Rights Reserved.

### Legal Disclaimer

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

### Information

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office (<a href="www.infineon.com">www.infineon.com</a>).

### Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office.

Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.